

# **APN6516 30V N-Channel Enhancement Mode MOSFET**

### **General Description**

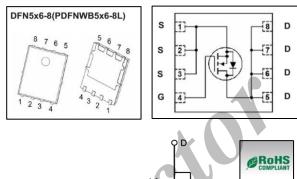
APN6516 combines advanced MOSFET technology with a low resistance package to provide extremely low RDS(ON). This device is most suitable to load-switch or DC/DC conversion applications.

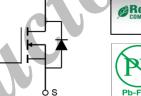
### **Applications**

- DC/DC Converters in Computing, Servers, and POL
- Isolated DC/DC Converters in Telecom and Industrial

### **Product Summary**

$ m V_{DS}$	30V
IDMAX (at $V_{GS} = 10V$ )	32A
$R_{DS(ON)}$ (at $V_{GS} = 10V$ )	< 5mΩ
$R_{DS(ON)}$ (at $V_{GS} = 4.5V$ )	< 8mΩ







### Absolute Maximum Ratings (Ta = 25°C unless otherwise specified)

Parameter		Symbol	Rating	Unit	
Drain-Source Voltage		VDS	30	V	
Gate-Source Voltage		Vgs	±20	V	
Continuous Drain Current <sup>G</sup>	Tc=25°C	Ip	32		
	Tc=100℃		25		
Pulsed Drain Current <sup>C</sup>		Ідм	127	A	
Continuous Drain Current	TA=25°C	IDSM	27	^	
	TA=70°C	IDSM	22		
Avalanche Current <sup>C</sup>		las	34		
Avalanche Energy L = 0.05 mH <sup>C</sup>		Eas	29	mJ	
Vps Spike	100ns	VSPIKE	36	V	
Davies Dissipation B	Tc=25°C	PD	25	W	
Power Dissipation <sup>B</sup>	Tc=100℃		10		
Same Significant A	TA=25°C	PDSM	6	l vv	
Power Dissipation A	TA=70°C	PDSM	3.8		
Thermal Resistance.Junction- to-Ambient A	t ≤ 10s	RthJA	21		
Thermal Resistance.Junction- to-Ambient AD	Steady-State	RthJA	53	°C/W	
Thermal Resistance.Junction- to-Case	Steady-State	RthJC 5			
Junction Temperature		TJ	150	°C	
Storage Temperature Range		Tstg	-55 to 150	℃	



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### Electrical Characteristics (T<sub>I</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Drain-Source Breakdown Voltage	BVDSS	$I_D = 250 \mu A$ , $V_{GS} = 0V$	30			V
Zero Gate Voltage Drain Current	Inss	Vps = 30 V, Vgs = 0 V			1	
Zero Gate Voltage Drain Current	IDSS	Vps = 30 V, Vgs = 0 V, TJ = 55 ℃			5	μΑ
Gate to Source Leakage Current	Igss	Vps = 0 V, Vgs = ±20 V			±100	nA
Gate to Source Threshold Voltage	VGS(th)	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2		2.2	V
		Vgs = 10 V, ID = 20 A			5	
Static Drain-Source On-Resistance	RDS(On)	Vgs = 10 V, ID = 20 A, TJ = 125 ℃			8	mΩ
		Vgs = 4.5 V, ID = 20 A			8	
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 20 A		83		S
Input Capacitance	Ciss	ì		1229	7	
Output Capacitance	Coss	Vgs = 0 V, Vps = 15 V, f = 1 MHz		526		pF
Reverse Transfer Capacitance	Crss			83		
Gate Resistance	Rg	Vgs = 0 V, Vps = 0 V, f = 1 MHz	0.8		2.6	Ω
Total Gate Charge	Qg(10V)			24	33	
Total Gate Charge	Qg(4.5V)	Vgs = 10V, Vps = 15 V, Jp = 20 A		12	17	nC
Gate Source Charge	Qgs	VGS = 10V, VDS = 15 V, 16 = 20 A		4		nC
Gate Drain Charge	Qgd			5.5		
Turn-On DelayTime	td(on)			7.0		
Turn-On Rise Time	tr	$V_{GS} = 10V$ , $V_{DS} = 15 V$ , $R_L = 0.75 \Omega$ ,		4.8		
Turn-Off DelayTime	td(off)	RGEN = 3 Ω		24.0		ns
Turn-Off Fall Time	tr			5.8		
Body Diode Reverse Recovery Time	trr	15 - 20 A di/di = 500 A/va		12.6		
Body Diode Reverse Recovery Charge	Qrr	$I_F = 20 \text{ A}, d_1/d_1 = 500 \text{ A}/\mu\text{s}$		15.2		nC
Maximum Body-Diode Continuous Current	ls				30	Α
Diode Forward Voltage	Vsp	Vgs = 0 V, Is = 1 A			1	V

#### Notes:

- A. The value of ReJA is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_{A}=25^{\circ}C.\ The\ Power\ dissipation\ P_{DSM}\ is\ based\ on\ R_{BJA}\ and\ the\ maximum\ allowed\ junction\ temperature\ of\ 150^{\circ}C.\ The\ value\ properties and\ the\ properties are considered by the properties of\ properties and\ properties are considered by the properties of\ properties are considered by the properties are c$
- I have 20°C. In experience of 150°C. The in any given application depends on the user's specific board design.

  B. The power dissipation Po is based on Taleuxe =150°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation jimit for cases where additional heatsinking is used.

  C. Single pulse width limited by junction temperature Taleuxe =150°C.

  D. The Raw is the sum of the thermal impedance from junction to case Raw and case to ambient.

  E. The static characteristics in Figures 1 to 6 are obtained using <300us pulses, duty cycle 0.5% max.

  E. These curves are based on the junction the case themself impedance which is measured with the device mounted to a life.

- F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of Tajawaj=150°C. The SOA curve provides a single pulse rating.
- G. The maximum current rating is package limited.
- H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with Ta=25°C.

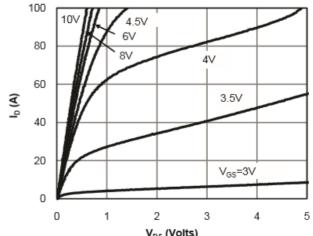
## **Ordering Information**

Ordering Part Number	Package	MOQ
APN6516	DFN5x6-8 (PDFNWB5x6-8L)	5,000 pcs / reel

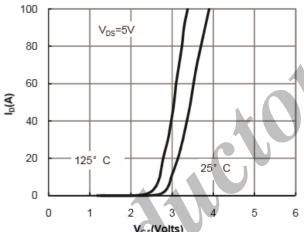
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### • Typical Characteristics



V<sub>DS</sub> (Volts) Fig 1: On-Region Characteristics (Note E)



V<sub>GS</sub>(Volts)
Figure 2: Transfer Characteristics (Note E)

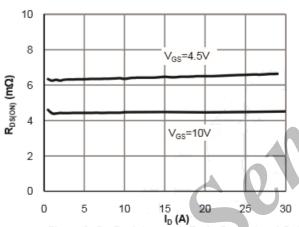


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

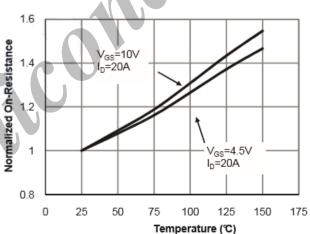


Figure 4: On-Resistance vs. Junction Temperature
(Note E)

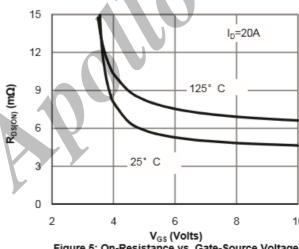


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

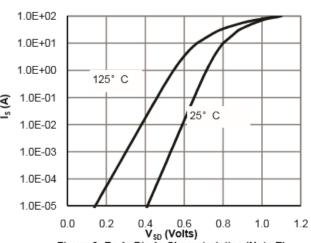


Figure 6: Body-Diode Characteristics (Note E)



### • Typical Characteristics

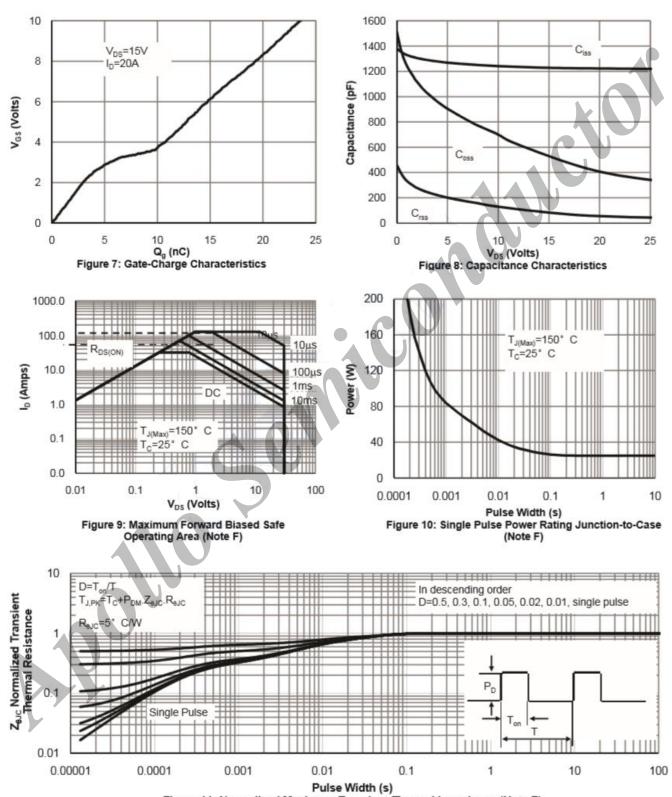
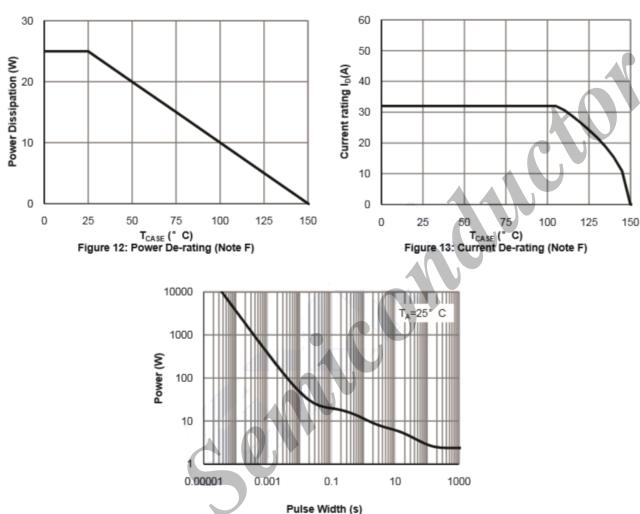


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



### • Typical Characteristics



Pulse Width (s)
Figure 14: Single Pulse Power Rating Junction-toAmbient (Note H)

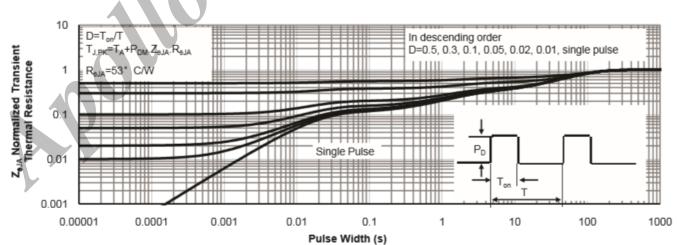
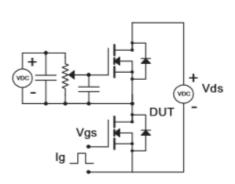
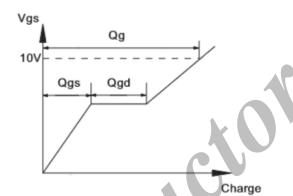


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

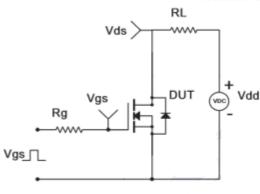


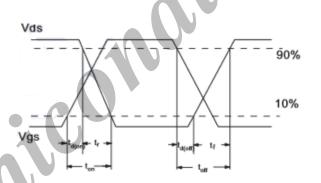
### Gate Charge Test Circuit & Waveform



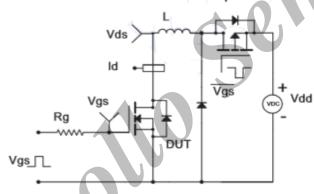


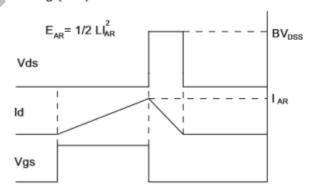
#### Resistive Switching Test Circuit & Waveforms



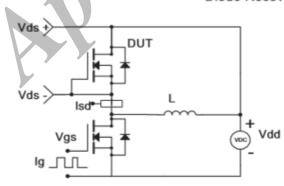


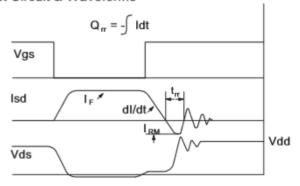
#### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





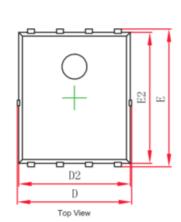
#### Diode Recovery Test Circuit & Waveforms

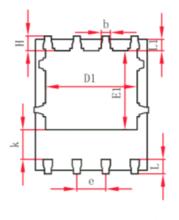




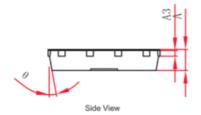


## • DFN5x6-8(PDFNWB5x6-8L) Package Outline Dimensions



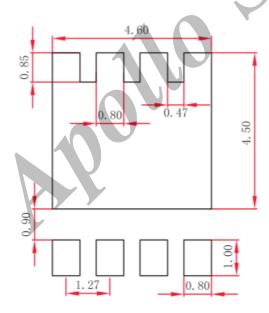


Bottom View



iew					
D. ot of	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Λ	0,900	1.000	0.035	0.039	
A3	0.254	REF.	0. 010REF.		
D	4.941	5.096	0.195	0. 201	
Е	5.974	6.126	0. 235	0.241	
D1	3.910	4.110	0.154	0.162	
E1	3. 375	3.575	0.133	0.141	
D2	4.824	4.976	0.190	0.196	
E2	5. 674	5.826	0. 223	0. 229	
- k	1.190	1.390	0. 047	0.055	
b	0.350	0.450	0.014	0.018	
e	1, 270		0. 050TYP.		
L	0.559	0.711	0.022	0.028	
L1					
	0.424	0.576	0.017	0.023	
H 0	0. 424 0. 574 10*	0.576 0.726 12°	0. 017 0. 023 10*	0. 023 0. 029 12°	

# ■ DFN5x6-8(PDFNWB5x6-8L) Suggested Pad Layout



#### Note:

- 1. Controlling dimension:in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

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